

U.S. Department of Commerce, Patent and Trademark	Atty. Docket No.	Application No.
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	TNCR.207US1	10/659,556
	Applicant(s)	Conf. No.
JUN 18 2004	Vaez-Iravani et al.	3091
	Filing Date	Group
	September 9, 2003	2877

U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
M	1	4,314,763	2/1982	Steigmeier et al.			
B	2	4,378,159	3/1983	Galbraith			
B	3	4,391,524	7/1983	Steigmeier et al.			
B	4	4,423,331	12/1983	Koizumi et al.			
B	5	4,479,714	10/1984	Lehrer			
B	6	4,508,450	4/1985	Ohshima et al.			
B	7	4,523,841	6/1985	Brunsting et al.			
B	8	4,526,468	7/1985	Steigmeier et al.			
B	9	4,598,997	7/1986	Steigmeier et al.			
B	10	4,735,504	4/1998	Tycko			
B	11	4,744,663	5/1988	Hamashima et al.			
B	12	4,794,265	12/1988	Quackenbos et al.			
B	13	4,893,932	1/1990	Knoellenberg			
B	14	4,898,471	2/1990	Stonestrom et al.			
B	15	4,929,845	5/1990	Amir et al.			
B	16	5,076,692	12/1991	Neukermans et al.			
B	17	5,108,176	4/1992	Malim et al.			
B	18	5,153,668	10/1992	Katzir et al.			
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B	20	5,270,794	12/1993	Tsujā et al.			
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B	28	5,530,550	6/1996	Nikoonahad et al.			
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B	30	5,798,829	8/1998	Vaez-Iravani et al.			

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MS	31	5,798,831	8/1998	Hagiwara			
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MS	33	6,104,945	8/2000	Modell et al.			
MS	34	6,201,601	3/2001	Vaez-Iravani et al.			
MS	35	6,271,916	8/2001	Marxer et al.			
MS	36	6,538,730	3/2003	Vaez-Iravani et al.			
Foreign Patent Documents							
							Translation
		Document	Date	Country	Class	Subclass	Yes No
MS	37	PCTUS9615354	9/1996	International			
MS	38	JP 63-14830	1/1988	Japan			Abstract
MS	39	JP 63-140904	6/1988	Japan			X
MS	40	JP 62-85449	11/1998	Japan			Abstract
MS	41	WO 00/00874	1/2000	WIPO			
MS	42	WO 00/00873	1/2000	WIPO			
MS	43	WO 00/02037	1/2000	WIPO			
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
MS	44	"Requirements for Future Surface Inspection Equipment for Bare Silicon Surfaces," P. Wagner et al., Wacker-Chemitronic GmbH, Burghausen, Germany, W. Baylies, BayTech Group, Weston Massachusetts					
MS	45	"The Importance of Media Refractive Index in Evaluating Liquid and Surface Microcontamination Measurements," R. Knollenberg et al., <i>The Journal of Environment Sciences</i> , Mar/Apr. 1987					
MS	46	"Surface Inspection System for Estimation of Wafer," Y. Yatsugake et al., <i>Hitachi Engineering Technical Report</i> , Vol. 11, January 1996, pp. 21-26 (with translation)					
MS	47	Figure, Hitachi Electronics Engineering Co., Ltd., presented by Etsuro Morita of Mitsubishi Materials Silicon Corp. in a presentation entitled "Exploration of COP and COP Defect Crystal Originated 'Particles'." at the 6 th International Workshop on 300 mm wafers on 12/5/96 in Makuhari, Japan					
MS	48	"Notification of Transmittal of the International Search Report or the Declaration" corresponding to PCT/US03/28593, filed 10 September 2003, 6 pages					
Examiner		Michael J. Stark		Date Considered		10-12-05	
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.							